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- Output Ports Have Equivalent 25-Ω Series Resistors, So No External Resistors Are Required
- ESD Protection Exceeds 2000 V Per MIL-STD-883, Method 3015; Exceeds 200 V Using Machine Model (C = 200 pF, R = 0)
- Latch-Up Performance Exceeds 500 mA Per JEDEC Standard JESD-17
- State-of-the-Art *EPIC*-II*B*[™] BiCMOS Design Significantly Reduces Power Dissipation
- Typical V_{OLP} (Output Ground Bounce) < 1 V at V_{CC} = 5 V, T_A = 25°C
- High-Impedance State During Power Up and Power Down
- Package Options Include Plastic Small-Outline (DW), Shrink Small-Outline (DB), and Thin Shrink Small-Outline (PW) Packages, Ceramic Chip Carriers (FK), Plastic (N) and Ceramic (J) DIPs, and Ceramic Flat (W) Packages

description

These octal buffers and line drivers are designed specifically to improve both the performance and density of 3-state memory address drivers, clock drivers, and bus-oriented receivers and transmitters. Together with the SN54ABT2240, SN74ABT2240A, and 'ABT2241, these devices provide the choice of selected combinations of inverting and noninverting outputs, symmetrical active-low output-enable (OE) inputs, and complementary OE and OE inputs. These devices feature high fan-out and improved fan-in.

The outputs, which are designed to sink up to 12 mA, include equivalent 25- Ω series resistors to reduce overshoot and undershoot.

When V_{CC} is between 0 and 2.1 V, the device is in the high-impedance state during power up or power down. However, to ensure the high-impedance state above 2.1 V, \overline{OE} should be tied to V_{CC} through a pullup resistor; the minimum value of the resistor is determined by the current-sinking capability of the driver.

The SN54ABT2244A is characterized for operation over the full military temperature range of -55° C to 125° C. The SN74ABT2244A is characterized for operation from -40° C to 85° C.



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PRODUCTION DATA information is current as of publication date. Products conform to specifications per the terms of Texas Instruments standard warranty. Production processing does not necessarily include testing of all parameters.



SN54ABT2244A J OR W PACKAGE
SN74ABT2244A DB, DW, N, OR PW PACKAGE
(TOP VIEW)

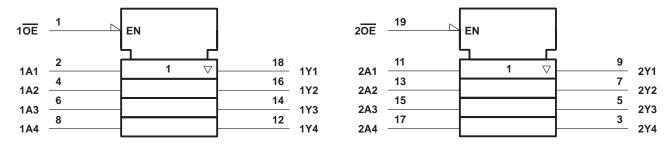
SN54ABT2244A . . . FK PACKAGE (TOP VIEW)

	2Y4 1A1 V _{CC} 2OE	
1A2	3 2 1 20 19 4 18	3 🛛 1 Y 1
2Y3	1 5 17	
1A2 2Y3 1A3	16 16	
2Y2 1A4	[]7 1:	
1A4	8 14	4 [1Y3
	9 10 11 12 13	
	2Y1 3ND 2A1 1Y4 2A2	

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FUNCTION TABLE (each buffer)								
INPUTS OUTPUT								
OE	Α	Y						
L	Н	Н						
L	L	L						
Н	Х	Z						

logic symbol[†]



9 2Y1

7 2Y2

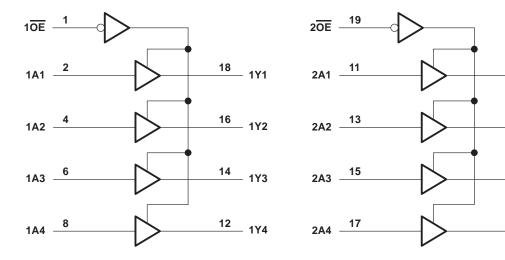
3 2Y4

2Y3

5

[†] This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

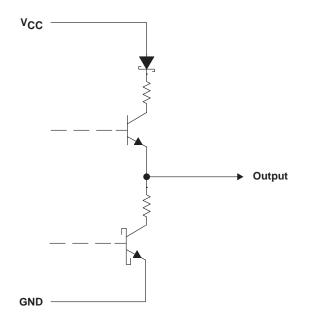
logic diagram (positive logic)





SN54ABT2244A, SN74ABT2244A OCTAL BUFFERS AND LINE/MOS DRIVERS WITH 3-STATE OUTPUTS SCBS106E – JANUARY 1991 – REVISED MAY 1997

schematic of Y outputs



absolute maximum ratings over operating free-air temperature range (unless otherwise noted)[†]

Supply voltage range, V_{CC} Input voltage range, V_I (see Note 1) Voltage range applied to any output in the high Current into any output in the low state, I_O Input clamp current, I_{IK} ($V_I < 0$) Output clamp current, I_{OK} ($V_O < 0$) Package thermal impedance, θ_{JA} (see Note 2):	or power-off state, V _O DB package DW package N package	-0.5 V to 7 V -0.5 V to 5.5 V -0.5 V to 5.5 V -18 mA -18 mA -50 mA -50 mA -115°C/W -97°C/W -67°C/W
	PW package	128°C/W
Storage temperature range, T _{stg}		–65°C to 150°C

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. The input and output negative-voltage ratings may be exceeded if the input and output clamp-current ratings are observed.

2. The package thermal impedance is calculated in accordance with EIA/JEDEC Std JESD51, except for through-hole packages, which use a trace length of zero.



SN54ABT2244A, SN74ABT2244A OCTAL BUFFERS AND LINE/MOS DRIVERS WITH 3-STATE OUTPUTS SCBS106E – JANUARY 1991 – REVISED MAY 1997

recommended operating conditions (see Note 3)

			SN54AB	SN54ABT2244A		SN74ABT2244A		
		Ē		MAX	MIN	MAX	UNIT	
VCC	Supply voltage		4.5	5.5	4.5	5.5	V	
VIH	High-level input voltage		2		2		V	
VIL	Low-level input voltage			0.8		0.8	V	
VI	Input voltage		0	VCC	0	VCC	V	
ЮН	High-level output current			-24		-32	mA	
IOL	Low-level output current			12		12	mA	
$\Delta t / \Delta v$	Input transition rise or fall rate Outputs enabled			5		5	ns/V	
Δt/ΔV _{CC}	Power-up ramp rate		200		200		μs/V	
ТА	Operating free-air temperature		-55	125	-40	85	°C	

NOTE 3: Unused inputs must be held high or low to prevent them from floating.



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electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

	METER	TEST CONDITIONS		T _A = 25°C		SN54ABT2244A		A SN74ABT2244A		UNIT	
PARAI	WEIER	TEST CON	NDITIONS	MIN	TYP†	MAX	MIN	MAX	MIN	MAX	UNIT
VIK		V _{CC} = 4.5 V,	lj = -18 mA			-1.2		-1.2		-1.2	V
		V _{CC} = 4.5 V,	I _{OH} = -3 mA	2.5			2.5		2.5		
VOH	V _{CC} = 5 V,	I _{OH} = -3 mA	3			3		3			
vОн		V _{CC} = 4.5 V	I _{OH} = -24 mA	2			2				v
		VCC = 4.5 V	I _{OH} = -32 mA	2*					2		
VOL		V _{CC} = 4.5 V,	I _{OL} = 12 mA			0.8		0.8		0.8	V
V _{hys}					100						mV
Ц		V _{CC} = 5.5 V,	$V_I = V_{CC}$ or GND			±1		±1		±1	μΑ
I _{OZPU} ‡	ţ	$V_{CC} = 0 \text{ to } 2.1 \text{ V},$ $V_{O} = 0.5 \text{ V to } 2.7 \text{ V}, \overline{O}$	Ē = X			±50		±50		±50	μA
IOZPD‡	ŧ	$V_{CC} = 2.1 V \text{ to } 0,$ $V_{O} = 0.5 V \text{ to } 2.7 V, \overline{OE} = X$				±50		±50		±50	μA
IOZH		V_{CC} = 2.1 V to 5.5 V, V_{O} = 2.7 V, $\overline{OE} \ge 2$ V				10		50		10	μΑ
I _{OZL}		$V_{CC} = 2.1 \text{ V to } 5.5 \text{ V}, \text{ V}_{O} = 0.5 \text{ V}, \overline{\text{OE}} \ge 2 \text{ V}$				-10		-50		-10	μΑ
l _{off}		$V_{CC} = 0,$	$V_{I} \text{ or } V_{O} \leq 4.5 \text{ V}$			±100				±100	μΑ
ICEX		$V_{CC} = 5.5 V,$ $V_{O} = 5.5 V$	Outputs high			50		50		50	μA
ΙΟ§		V _{CC} = 5.5 V,	V _O = 2.5 V	-50	-100	-180	-50	-180	-50	-180	mA
			Outputs high		1	250		250		250	μΑ
ICC		$V_{CC} = 5.5 \text{ V}, I_O = 0,$ $V_I = V_{CC} \text{ or GND}$	Outputs low		24	30		30		30	mA
			Outputs disabled		0.5	250		250		250	μΑ
	Data	$V_{CC} = 5.5 V$, One input at 3.4 V,	Outputs enabled			1.5		1.5		1.5	
ΔI_{CC}	inputs Other inputs at V _{CC} or GND		Outputs disabled			0.05		0.05		0.05	mA
	Control inputs	V_{CC} = 5.5 V, One input Other inputs at V_{CC} or				1.5		1.5		1.5	
Ci		VI = 2.5 V or 0.5 V			4						pF
Co		$V_{O} = 2.5 \text{ V or } 0.5 \text{ V}$			5.5						pF

* On products compliant to MIL-PRF-38535, this parameter does not apply.

[†] All typical values are at $V_{CC} = 5 V$.

[‡] This parameter is characterized, but not production tested.

§ Not more than one output should be tested at a time, and the duration of the test should not exceed one second.

This is the increase in supply current for each input that is at the specified TTL voltage level rather than V_{CC} or GND.



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switching characteristics over recommended ranges of supply voltage and operating free-air temperature, $C_L = 50 \text{ pF}$ (unless otherwise noted) (see Figure 1)

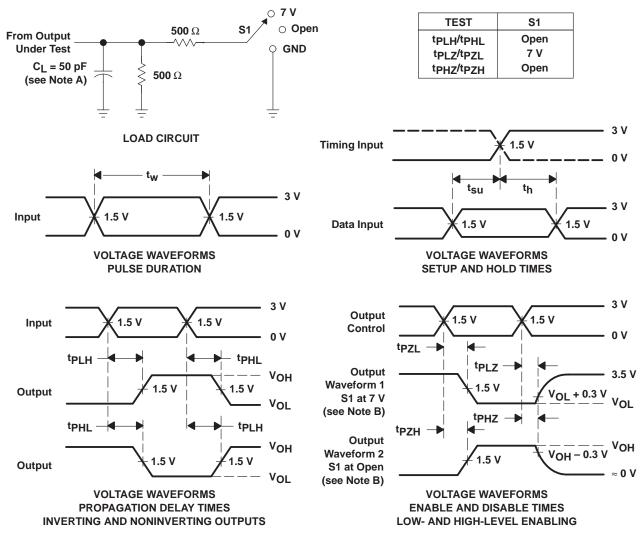
			SN54ABT2244A					
PARAMETER	FROM (INPUT)	TO (OUTPUT)	V _{CC} = 5 V, T _A = 25°C			MIN MAX		UNIT
		MIN	TYP	MAX				
t _{PLH}	A	V	1	3.4	4.4	1	5.3	ns
^t PHL		I	1	4.5	6.3	1	6.8	115
^t PZH	ŌĒ	V	1.1	3.8	5.5	1.1	6.5	ns
tPZL		I	2.1	6.3	9	2.1	10.2	115
^t PHZ	OE	v	2.1	4.5	6.9	2.1	7	ns
^t PLZ	UE	ĩ	1.7	4.3	6.9	1.7	7.4	115

switching characteristics over recommended ranges of supply voltage and operating free-air temperature, $C_L = 50 \text{ pF}$ (unless otherwise noted) (see Figure 1)

				SN7	4ABT22	44A		
PARAMETER	FROM (INPUT)	TO (OUTPUT)	V _{CC} = 5 V, T _A = 25°C			MIN MAX	МАХ	UNIT
			MIN	TYP	MAX			
^t PLH	A	×	1	3.4	4.3	1	4.7	ns
^t PHL		I	1	4.5	5.3	1	5.6	115
^t PZH	ŌĒ	V	1.1	3.8	4.8	1.1	5.5	ns
^t PZL		I	2.1	6.3	7.3	2.1	8.3	115
^t PHZ	OE	v	2.1	4.5	5.6	2.1	6.6	ns
^t PLZ	UE	1	1.7	4.3	5.3	1.7	5.8	115



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PARAMETER MEASUREMENT INFORMATION

NOTES: A. CL includes probe and jig capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 C. All input pulses are supplied by generators having the following characteristics: PRR ≤ 10 MHz, Z_Q = 50 Ω, t_r ≤ 2.5 ns, t_f ≤ 2.5 ns.
- C. All input puises are supplied by generators having the following characteristics: PRR \leq 10 MHz, 2O = 50.02, t_f ≤ 2.5 ns, t_f ≤ 2

D. The outputs are measured one at a time with one transition per measurement.

Figure 1. Load Circuit and Voltage Waveforms



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